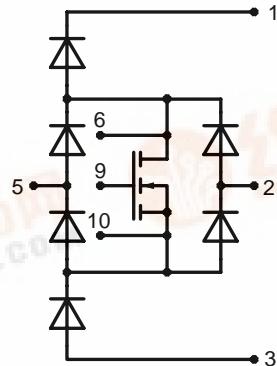


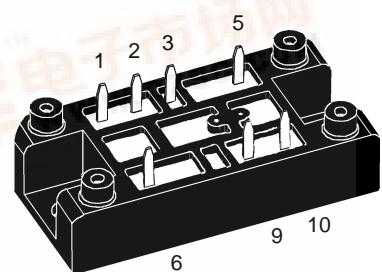
Rectifier Module for Three Phase Power Factor Correction

Using fast recovery epitaxial diodes and MOSFET

V_{RRM} (Diode)	V_{DSS}	Type
V	V	
600	500	VUM 25-05E



$V_{DSS} = 500 \text{ V}$
 $I_{D25} = 35 \text{ A}$
 $R_{DS(on)} = 0.12 \Omega$



Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_{VJ} = 25^\circ\text{C}$ to 150°C	500	V	
V_{DGR}	$T_{VJ} = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 10 \text{ k}\Omega$	500	V	
V_{GS}	Continuous	± 20	V	
I_D	$T_s = 85^\circ\text{C}$	24	A	
I_D	$T_s = 25^\circ\text{C}$	35	A	
I_{DM}	$T_s = 25^\circ\text{C}, t_p = ①$	95	A	
P_D	$T_s = 85^\circ\text{C}$	170	W	
I_S	$V_{GS} = 0 \text{ V}, T_s = 25^\circ\text{C}$	24	A	
I_{SM}	$V_{GS} = 0 \text{ V}, T_s = 25^\circ\text{C}, t_p = ①$	95	A	
V_{RRM}	$T_s = 85^\circ\text{C}$, rectangular $\delta = 0.5$	600	V	
I_{dAV}		40	A	
I_{FSM}	$T_{VJ} = 45^\circ\text{C}, t = 10 \text{ ms}$ (50 Hz) $t = 8.3 \text{ ms}$ (60 Hz)	300	A	
	$T_{VJ} = 150^\circ\text{C}, t = 10 \text{ ms}$ (50 Hz) $t = 8.3 \text{ ms}$ (60 Hz)	320	A	
		260	A	
		280	A	
P	$T_s = 85^\circ\text{C}$	36	W	
T_{VJ}		-40...+150	$^\circ\text{C}$	
T_{JM}		150	$^\circ\text{C}$	
T_{stg}		-40...+150	$^\circ\text{C}$	
V_{ISOL}	50/60 Hz $I_{ISOL} \leq 1 \text{ mA}$	$t = 1 \text{ min}$ $t = 1 \text{ s}$	3000 3600	V~ V~
M_d Weight	Mounting torque (M5)		2-2.5/18-22 Nm/lb.in.	
			35	g

Features

- Package with DCB ceramic base plate
- Soldering connections for PCB mounting
- Isolation voltage 3600 V~
- Low $R_{DS(on)}$ HDMOS™ process
- Low package inductance for high speed switching
- Ultrafast diodes
- Kelvin source for easy drive

Applications

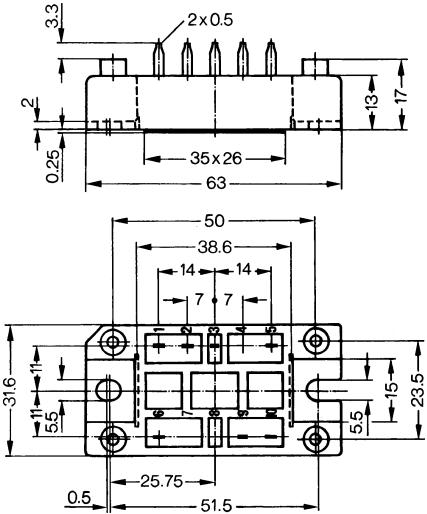
- Three phase input rectifier with power factor correction consisting of three modules VUM 25-05
- For power supplies, UPS, SMPS, drives, welding etc.

Advantages

- Reduced harmonic content of input currents corresponding to standards
- Rectifier generates maximum DC power with a given AC fuse
- Wide input voltage range
- No external isolation
- Easy to mount with two screws
- Suitable for wave soldering
- High temperature and power cycling capability

① Pulse width limited by T_{VJ}
IXYS reserves the right to change limits, test conditions and dimensions.

Symbol	Test Conditions	Characteristic Values			Dimensions in mm (1 mm = 0.0394")
		min.	typ.	max.	
V_{DSS}	$V_{GS} = 0 \text{ V}, I_D = 2 \text{ mA}$	500		V	$(T_{VJ} = 25^\circ\text{C}, \text{unless otherwise specified})$  MOSFET
$V_{GS(th)}$	$V_{DS} = 20 \text{ V}, I_D = 20 \text{ mA}$	2		V	
I_{GSS}	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			$\pm 500 \text{ nA}$	
I_{DSS}	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$			2 mA	
$R_{DS(on)}$	$T_{VJ} = 25^\circ\text{C}$	0.12	Ω		
R_{Gint}	$T_{VJ} = 25^\circ\text{C}$	1.5	Ω		
g_{fs}	$V_{DS} = 15 \text{ V}, I_{DS} = 12 \text{ A}$	30		S	
V_{DS}	$I_{DS} = 24 \text{ A}, V_{GS} = 0 \text{ V}$		1.5	V	
$t_{d(on)}$	$\left. \begin{array}{l} V_{DS} = 250 \text{ V}, I_{DS} = 12 \text{ A}, V_{GS} = 10 \text{ V} \\ Z_{\text{gen.}} = 1 \Omega, \text{ L-load} \end{array} \right\}$	100	ns		
$t_{d(off)}$	$\left. \begin{array}{l} V_{DS} = 250 \text{ V}, I_{DS} = 12 \text{ A}, V_{GS} = 10 \text{ V} \\ Z_{\text{gen.}} = 1 \Omega, \text{ L-load} \end{array} \right\}$	220	ns		
C_{iss}	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	8.5		nF	
C_{oss}		0.9		nF	
C_{rss}		0.3		nF	
Q_g	$V_{DS} = 250 \text{ V}, I_D = 12 \text{ A}, V_{GS} = 10 \text{ V}$	350		nC	
R_{thJS}			0.38	K/W	
V_F	$I_F = 22 \text{ A}; T_{VJ} = 25^\circ\text{C}$ $T_{VJ} = 150^\circ\text{C}$		1.65	V	
			1.4	V	
I_R	$V_R = 600 \text{ V}, T_{VJ} = 25^\circ\text{C}$ $V_R = 480 \text{ V}, T_{VJ} = 25^\circ\text{C}$ $T_{VJ} = 125^\circ\text{C}$		1.5	mA	
			0.25	mA	
			7	mA	
V_{TO}	For power-loss calculations only		1.14	V	 Diodes
r_T	$T_{VJ} = 125^\circ\text{C}$		10	$m\Omega$	
I_{RM}	$I_F = 30 \text{ A}; -di_F/dt = 240 \text{ A}/\mu\text{s}$ $V_R = 350 \text{ V}, T_{VJ} = 100^\circ\text{C}$	10	11	A	
R_{thJS}				1.8	K/W



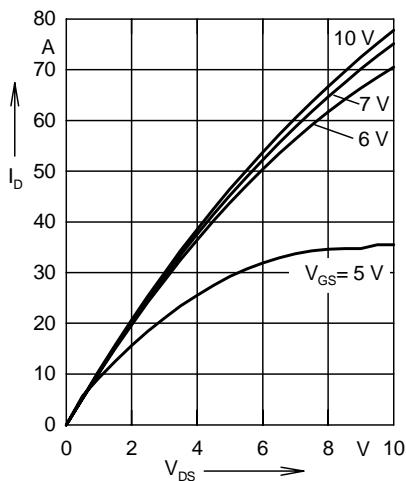


Fig. 1 Typ. output characteristic
 $I_D = f (V_{DS})$ (MOSFET)

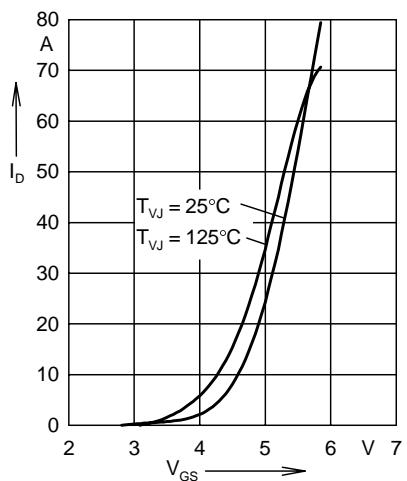


Fig. 2 Typ. transfer characteristics
 $I_D = f (V_{GS})$ (MOSFET)

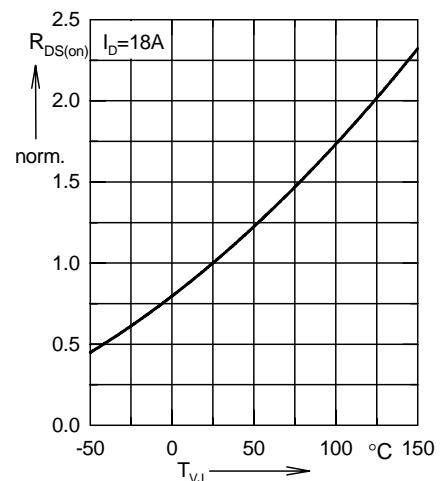


Fig. 3 Typ. normalized
 $R_{DS(on)} = f (T_{VJ})$ (MOSFET)

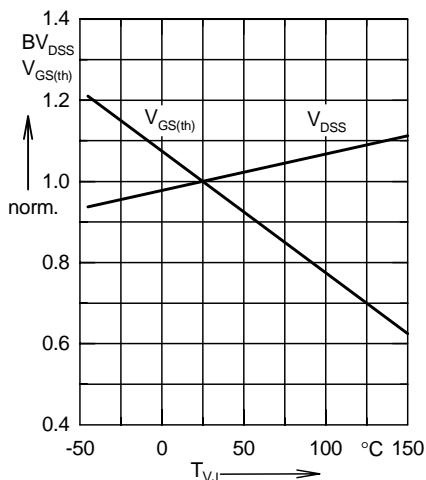


Fig. 4 Typ. normalized $BV_{DSS} = f (T_{VJ})$,
 $V_{GS(th)} = f (T_{VJ})$ (MOSFET)

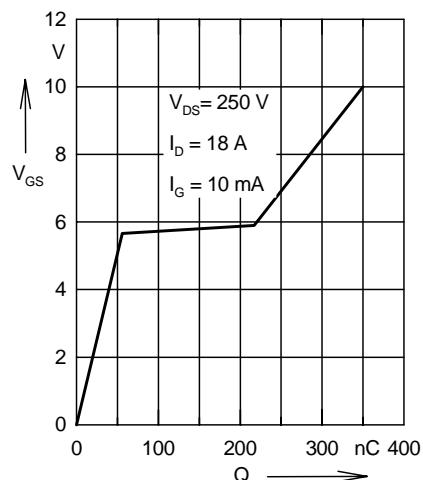


Fig. 5 Typ. turn-on gate charge
characteristics, $V_{GS} = f (Q_g)$ (MOSFET)

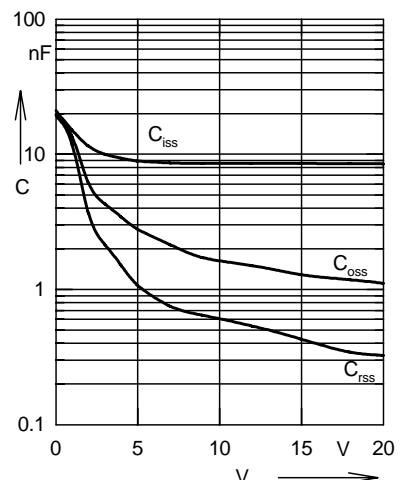


Fig. 6 Typ. capacitances $C = f (V_{DS})$,
 $f = 1 \text{ MHz}$ (MOSFET)

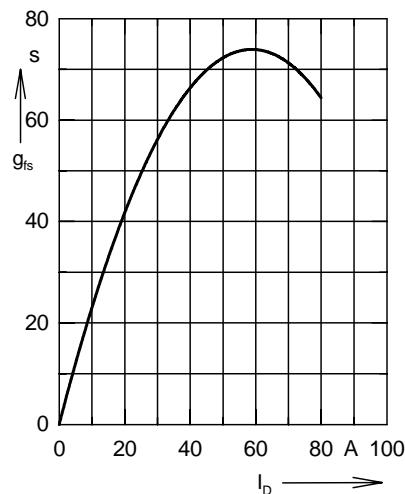


Fig. 7 Typ. transconductance,
 $g_{fs} = f (I_D)$ (MOSFET)

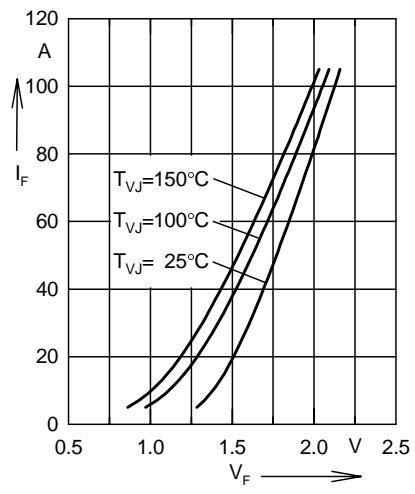


Fig. 8 Forward current versus
voltage drop (Diodes)

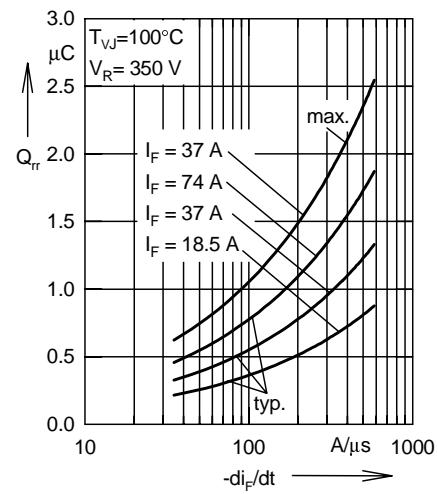


Fig. 9 Recovery charge versus $-di_F/dt$
(Diodes)

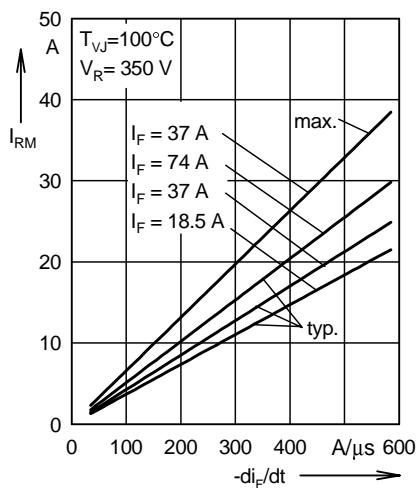


Fig. 10 Peak reverse current versus $-di_F/dt$ (Diodes)

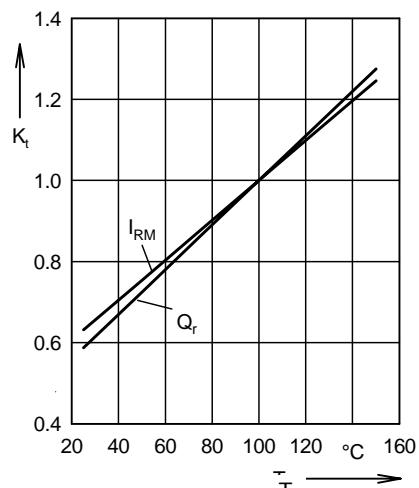


Fig. 11 Dynamic parameters versus junction temperature (Diodes)

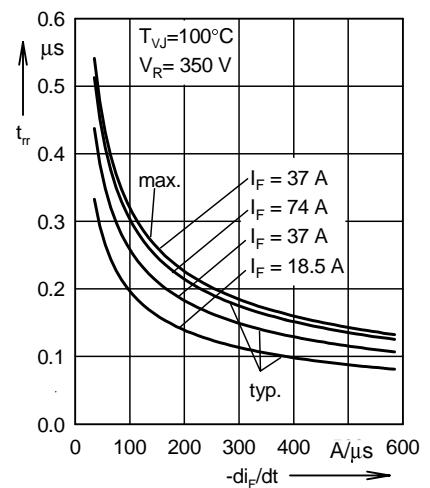


Fig. 12 Recovery time versus $-di_F/dt$ (Diodes)

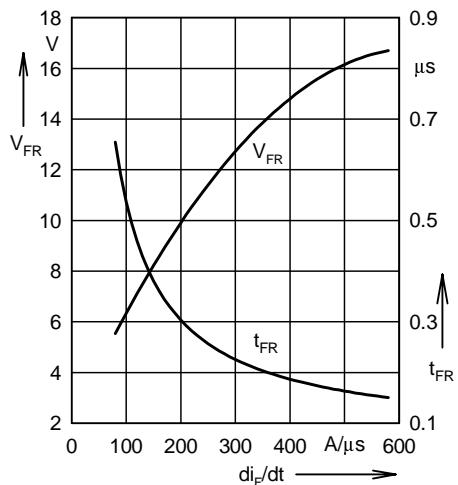


Fig. 13 Peak forward voltage versus $-di_F/dt$ (Diodes)

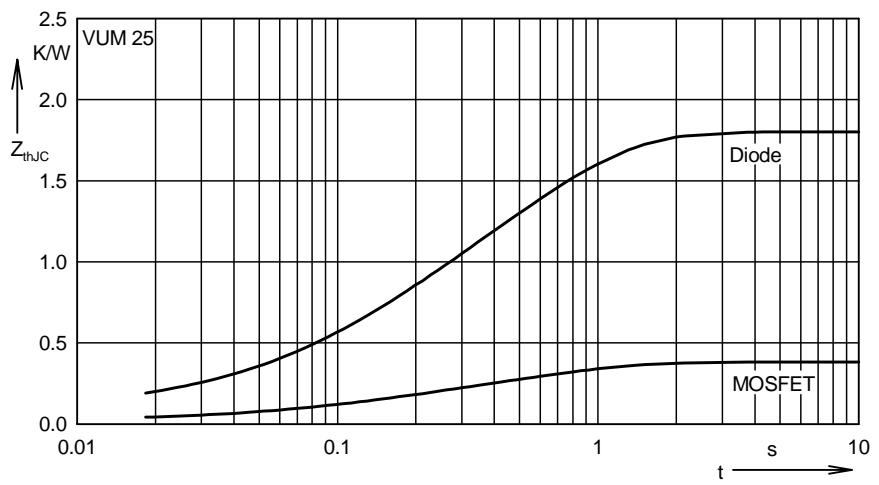


Fig. 14 Transient thermal impedance junction to case for all devices